

EMC TEST REPORT

According to FCC CFR47 Part 18 Subpart C

JOB Number :

1. This test reports does not constitute an endorsement by NIST/NVLAP or U.S Government.
2. This test report is to certify that the tested device properly complies with the requirements of FCC Rules and Regulations Part 18 CFR47 Subpart C Intentional Radiators.
All tests necessary to show compliance to the requirements were and these results met the specifications requirement.

This laboratory is registered by the NIST/NVLAP, U.S.A.
The test reported herein have been performed in accordance with its terms of registration.



1. Test Laboratory : SAMSUNG ELECTRONICS CO., LTD.
416 Maetan 3 Dong, Paldal-Ku, Suwon City, Kyungki Do, Korea, 442-742

2. Identification of tested device

- 2.1 FCC ID : ACL AP5Y01
2.2 Device Name : MICROWAVE OVEN
2.3 Trade Name : Shanghai Matsushita Microwave Oven Co., Ltd
2.4 Model Number : NN-S563BFAPH
2.5 RF Output Power : 1350 W

3. Test Procedure and Items

- 3.1 FCC/OST MP-5 : 1986

4. Issued Date :

Tested by:

J. Y. Park

Jay Yong, PARK / Test Engineer

Reviewed by:

N. C. Park

No Cheon, PARK / Manager of EMC Lab.

Authorised by:

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Confirmed by:

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1. Product Description

The equipment under test is a microwave oven sold for consumer use.

Model : NN-S563BFAI is a 1350 W microwave oven with digital controls.

Installation Type: Inverter

< Magnetron >

Model : OM75PI(21) manufactured by Samsung Electronic Co., Ltd.

2. Test Facility

The Semi-anechoic chamber and Conducted measurement facilities used to collect the radiated data are located at 416 Maetan 3 Dong, Paldal-Ku, Suwon City, Kyungki Do, Korea.

The sites are constructed in conformance with the requirements of ANSI C63.4 and CISPR Publication 22.

3. Accreditation and Listing

The test facilities used to perform radiated and conducted emissions tests are accredited by National Voluntary Laboratory Accreditation Program for the specific of accreditation under Lab Code: 200447-0 to perform Electromagnetic Interference tests according to FCC PART 15 and CISPR 22 requirements.

No part of this report may be used to claim or imply product endorsement by NVLAP or any agency of the US Government. In addition, the test facilities are listed with Federal Communications Commission(Registration Number:98856, Anechoic Chamber #1).